

MOSFET

CoolSiC™ MOSFET 650 V G2

Built on Infineon's robust 2nd generation Silicon Carbide trench technology, the 650 V CoolSiC™ MOSFET delivers unparalleled performance, superior reliability, and great ease of use. It enables cost effective, highly efficient, and simplified designs to fulfill the ever-growing system and market needs.

Features

- · Ultra-low switching losses
- Benchmark gate threshold voltage, V_{GS(th)} = 4.5 V
- Robust against parasitic turn-on even with 0 V turn-off gate voltage
- Flexible driving voltage and compatible with bipolar driving scheme
- Robust body diode operation under hard commutation events
- .XT interconnection technology for best-in-class thermal performance

Benefits

- · Enables high efficiency and high power density designs
- Facilitates great ease of use and integration
- Provides the best price performance ratio compared to Industry's most ambitious roadmaps
- · Reduces the size, weight and bill of materials of the systems
- Enhances system robustness and reliability

Potential applications

- SMPS
- · Solar PV inverters
- · Energy storage and battery formation
- UPS
- · EV charging infrastructure
- Motor drives

Product validation

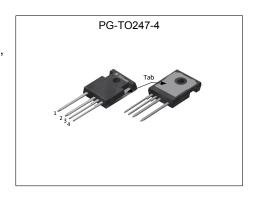
Fully qualified according to JEDEC for Industrial Applications

Please note: The source and driver source pins are not exchangeable. Their exchange might lead to malfunction.



Parameter	Value	Unit	
$V_{\rm DSS}$ over full $T_{\rm j,range}$	650	V	
R _{DS(on),typ}	6.7	mΩ	
R _{DS(on),max}	8.5	mΩ	
$Q_{G,typ}$	179	nC	
$I_{D,pulse}$	890	A	
Q _{oss} @ 400 V	337	nC	
E _{oss} @ 400 V	45.7	μJ	

Type / Ordering Code	Package	Marking	Related Links
IMZA65R007M2H	PG-TO247-4	65R007M2	see Appendix A



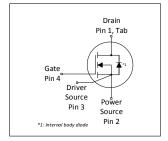










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1 Maximum ratings at $T_j = 25$ °C, unless otherwise specified.

Note: for optimum lifetime and reliability, Infineon recommends operating conditions that do not exceed 80% of the maximum ratings stated in this datasheet.

Table 2 Maximum ratings

Danamatan	Ol		Value	s	,	Nata / Taat Can dition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Continuous DC drain current ¹⁾	I _{DDC}	-	-	210 149	А	T _C = 25 °C T _C = 100 °C	
Peak drain current ²⁾	I _{DM}	-	-	890	Α	T _C = 25 °C, V _{GS} = 18 V	
Avalanche energy, single pulse	E _{AS}	-	-	848	mJ	$I_D = 31.8 \text{ A}, V_{DD} = 50 \text{ V}; \text{ see table } 11$	
Avalanche energy, repetitive	E AR	-	-	4.24	mJ	$I_D = 31.8 \text{ A}, V_{DD} = 50 \text{ V}; \text{ see table } 11$	
Avalanche current, single pulse	I _{AS}	-	-	31.8	Α	-	
MOSFET dv/dt ruggedness	dv/dt	-	-	200	V/ns	V _{DS} = 0400 V	
Gate source voltage (static) ³⁾	V _{GS}	-7	-	23	V	-	
Gate source voltage (transient)	V _{GS}	-10	-	25	V	$t_p \le 500 \text{ ns, duty cycle} \le 1 \%$	
Power dissipation	P _{tot}	-	-	625	W	T _C = 25 °C	
Storage temperature	T _{stg}	-55	-	150	°C	-	
Operating junction temperature	T _j	-55	-	175	°C	-	
Mounting torque	-	-	-	60	Ncm	M3 and M3.5 screws	
Continuous reverse drain current ¹⁾	I _{SDC}	-	-	210 130	А	V _{GS} = 18 V, T _C = 25 °C V _{GS} = 0 V, T _C = 25 °C	
Peak reverse drain current ²⁾	I _{SM}	-	-	890 276	А	$T_{\rm C}$ = 25 °C, $t_{\rm p}$ ≤ 250 ns $T_{\rm C}$ = 25 °C	
Insulation withstand voltage	V _{ISO}	-	-	n.a.	V	$V_{\rm rms}$, $T_{\rm C}$ = 25 °C, t = 1 min	

¹⁾ Limited by $T_{\rm J,max}$ ²⁾ Pulse width $t_{\rm pulse}$ limited by $T_{\rm j,max}$.
³⁾ The maximum gate-source voltage in the application design should be in accordance to IPC-9592B.



2 Thermal characteristics

Table 3 Thermal characteristics

Davamatav	Cymphal	Values			11	Note / Took Condition	
Parameter	Symbol	Symbol Min. Typ.		Max.	Unit	Note / Test Condition	
Thermal resistance, junction - case	R _{th(j-c)}	-	-	0.24	°C/W	Not subject to production test. Parameter verified by design/characterization according to JESD51-14.	
Soldering temperature, wavesoldering only allowed at leads	T_{sold}	-	-	260	°C	1.6 mm (0.063 in.) from case for 10 s	

3 Operating range

Table 4 Operating range

Doromotor	Cumbal	Values			Linit	Note / Test Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Recommended turn-on voltage	V _{GS(on)}	-	18	-	V	-	
Recommended turn-off voltage	V _{GS(off)}	-	0	-	V	-	

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4 Electrical characteristics at $T_j = 25$ °C, unless otherwise specified

Table 5 **Static characteristics**

Daniel de la constant		Values			T		
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source voltage	V _{DSS}	650	-	-	V	$V_{\rm GS}$ = 0 V, $I_{\rm D}$ = 2.97 mA	
Gate threshold voltage ¹⁾	V _{GS(th)}	3.5	4.5	5.6	V	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 29.7 \text{ mA}$	
Zero gate voltage drain current	I _{DSS}	-	1 10	75 -	μΑ	$V_{\rm DS} = 650 \text{ V}, \ V_{\rm GS} = 0 \text{ V}, \ T_{\rm j} = 25 \text{ °C} $ $V_{\rm DS} = 650 \text{ V}, \ V_{\rm GS} = 0 \text{ V}, \ T_{\rm j} = 175 \text{ °C} $	
Gate-source leakage current	I _{GSS}	-	-	100	nA	V _{GS} = 20 V, V _{DS} = 0 V	
Drain-source on-state resistance	R _{DS(on)}	- - -	8.7 6.7 6.1 11	- 8.5 - -	mΩ	$V_{\rm GS}$ = 15 V, $I_{\rm D}$ = 146.3 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 146.3 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 20 V, $I_{\rm D}$ = 146.3 A, $T_{\rm j}$ = 25 °C $V_{\rm GS}$ = 18 V, $I_{\rm D}$ = 146.3 A, $T_{\rm j}$ =175 °C	
Internal gate resistance R _{G,int}		-	1.0	-	Ω	f = 1 MHz	

 $^{^{1)}}$ Tested after 1 ms pulse at V_{GS} = +20 V. "Linear mode" operation is not recommended. For assessment of potential "linear mode" operation, please contact Infineon sales office.



Table 6 **Dynamic characteristics**

External parasitic elements (PCB layout) influence switching behavior significantly. Stray inductances and coupling capacitances must be minimized.

For layout recommendations please use provided application notes or contact Infineon sales office.

Davamatar	Comple of		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Input capacitance	Ciss	-	6359	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Reverse transfer capacitance	Crss	-	35	-	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output capacitance ¹⁾	Coss	-	471	613	pF	$V_{GS} = 0 \text{ V}, V_{DS} = 400 \text{ V}, f = 250 \text{ kHz}$	
Output charge ¹⁾	Qoss	-	337	439	nC	calculation based on Coss	
Effective output capacitance, energy related ²⁾	$C_{ m o(er)}$	-	571	-	pF	$V_{GS} = 0 \text{ V},$ $V_{DS} = 0400 \text{ V}$	
Effective output capacitance, time related ³⁾	C _{o(tr)}	-	844	-	pF	I_D = constant, V_{GS} = 0 V, V_{DS} = 0400 V	
Turn-on delay time	$t_{ m d(on)}$	-	22	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 146.3 \text{ A}, \ R_{\rm G,ext} = 5.2 \ \Omega; \ \text{see table } 10$	
Rise time	t _r	-	41	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 146.3 \text{ A}, \ R_{\rm G,ext} = 5.2 \ \Omega;$ see table 10	
Turn-off delay time	$t_{ m d(off)}$	-	53	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 146.3 \text{ A}, \ R_{\rm G,ext} = 5.2 \ \Omega;$ see table 10	
Fall time	t _f	-	20	-	ns	$V_{\rm DD} = 400 \text{ V}, \ V_{\rm GS} = 0/18 \text{ V}, \ I_{\rm D} = 146.3 \text{ A}, \ R_{\rm G,ext} = 5.2 \ \Omega;$ see table 10	
Turn-ON switching losses ⁴⁾	Eon	-	753	-	μJ	$V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ $I_{D} = 146.3 \text{ A}, R_{G,ext} = 5.2 \Omega$	
Turn-OFF switching losses ⁴⁾	E _{off}	-	1638	-	μJ	$V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V}, I_{D} = 146.3 \text{ A}, R_{G,ext} = 5.2 \Omega$	
Total switching losses ⁴⁾	E _{tot}	-	2391	-	μJ	$V_{DD} = 400 \text{ V}, V_{GS} = 0/18 \text{ V},$ $I_{D} = 146.3 \text{ A}, R_{G,ext} = 5.2 \Omega$	

Table 7 **Gate charge characteristics**

Doromotor	Cumbal	Values			11:4	Note / Took Condition	
Parameter	Symbol	Min. Typ.		Max.	Unit	Note / Test Condition	
Plateau gate to source charge	$Q_{GS(pl)}$	-	46	-	nC	$V_{\text{DD}} = 400 \text{ V}, I_{\text{D}} = 146.3 \text{ A}, V_{\text{GS}} = 0 \text{ to } 18 \text{ V}$	
Gate to drain charge	Q_{GD}	-	33	-	nC	$V_{\text{DD}} = 400 \text{ V}, I_{\text{D}} = 146.3 \text{ A},$ $V_{\text{GS}} = 0 \text{ to } 18 \text{ V}$	
Total gate charge	Q_G	-	179	-	nC	$V_{\rm DD}$ = 400 V, $I_{\rm D}$ = 146.3 A, $V_{\rm GS}$ = 0 to 18 V	

¹⁾ Maximum specification is defined by calculated six sigma upper confidence bound

PMAXIMUM specification is defined by calculated six sigma upper confidence both $C_{O(er)}$ is a fixed capacitance that gives the same stored energy as C_{oss} while V_{DS} is rising from 0 to 400 V.

3) $C_{o(tr)}$ is a fixed capacitance that gives the same charging time as C_{oss} while V_{DS} is rising from 0 to 400 V.

4) Values for 4-pin configuration based on TO-263-7 measurements; MOSFET used in half-bridge configuration without external diode

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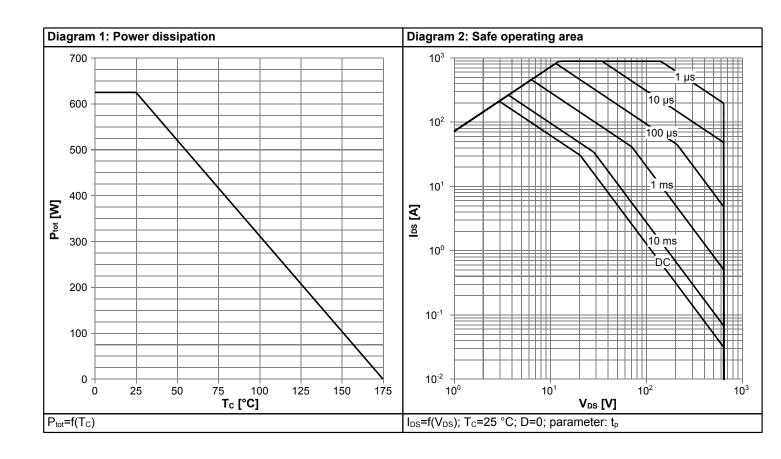


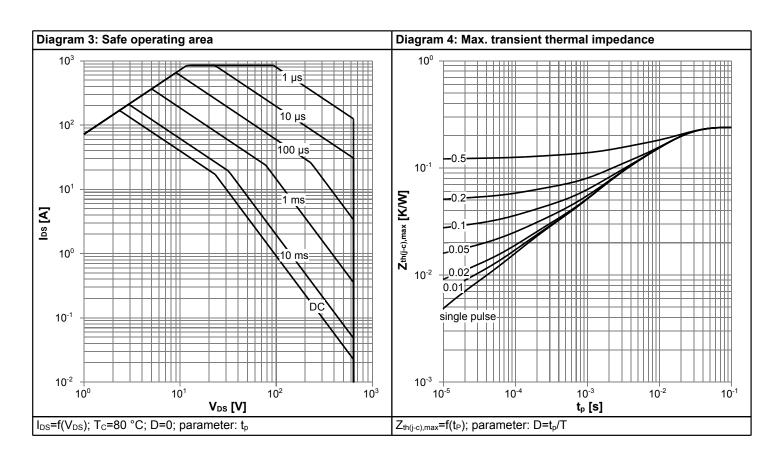
Table 8 Reverse diode characteristics

Damamatan	Cymahal		Values			Note / Took Condition	
Parameter	Symbol	Min.	Тур.	Max.	Unit	Note / Test Condition	
Drain-source reverse voltage	V_{SD}	-	4.3	-	V	$V_{GS} = 0 \text{ V}, I_S = 146.3 \text{ A}, T_j = 25 ^{\circ}\text{C}$	
MOSFET forward recovery time	t_{fr}	-	29.3 22.7	-	ns	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/µs}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/µs}; \text{ see table 9}$	
MOSFET forward recovery charge ¹⁾	Q_{fr}	-	362 607	-	nC	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/µs}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/µs}; \text{ see table 9}$	
MOSFET peak forward recovery current	I_{frm}	-	24.7 53.5	-	A	$V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 1000 \text{ A/µs}; \text{ see table 9}$ $V_{\rm DD} = 400 \text{ V}, I_{\rm S} = 146.3 \text{ A},$ $di_{\rm S}/dt = 4000 \text{ A/µs}; \text{ see table 9}$	

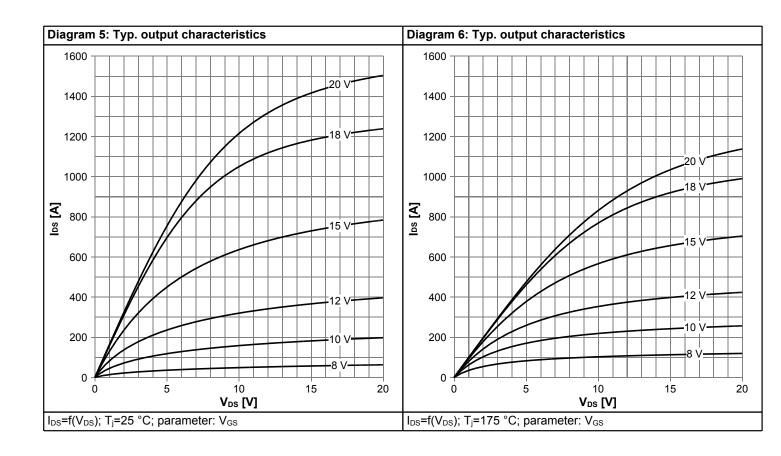


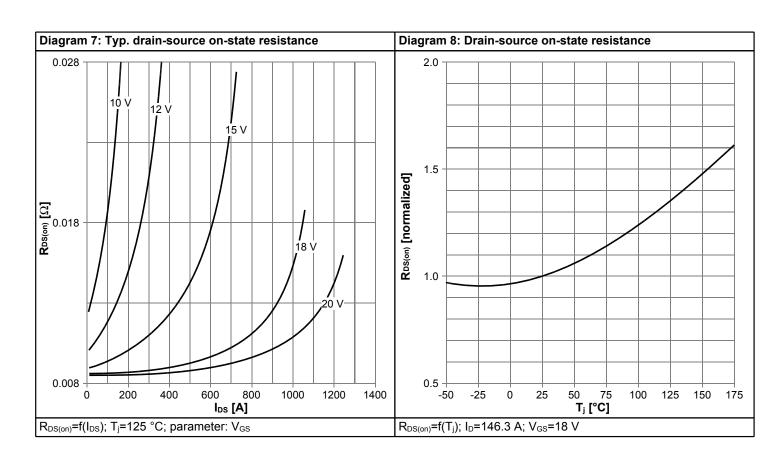
5 Electrical characteristics diagrams



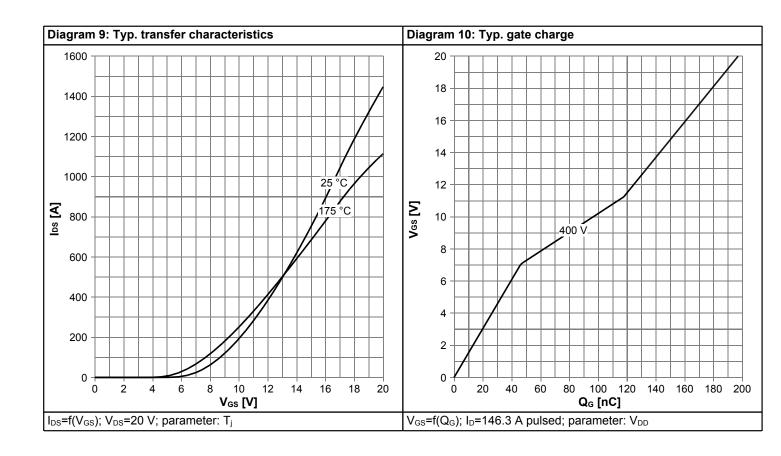


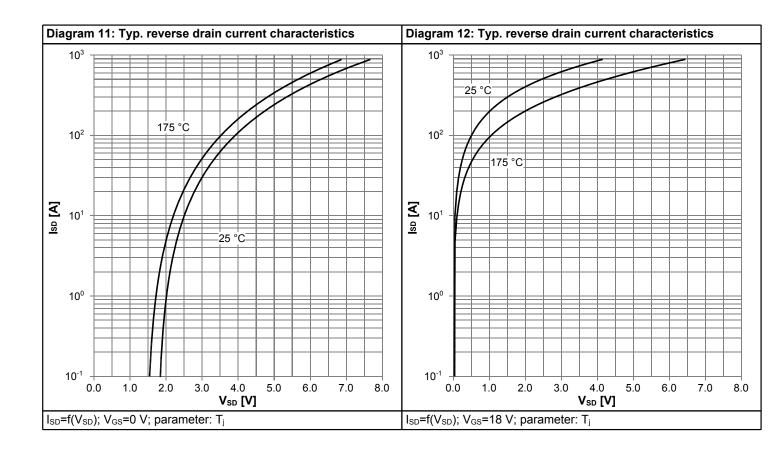




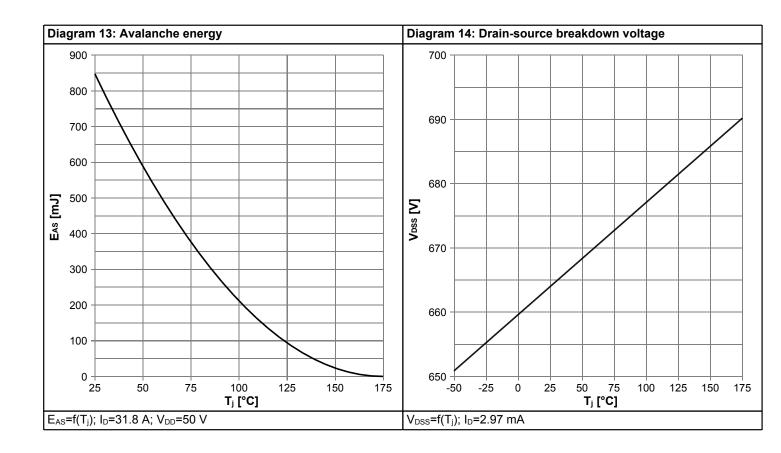


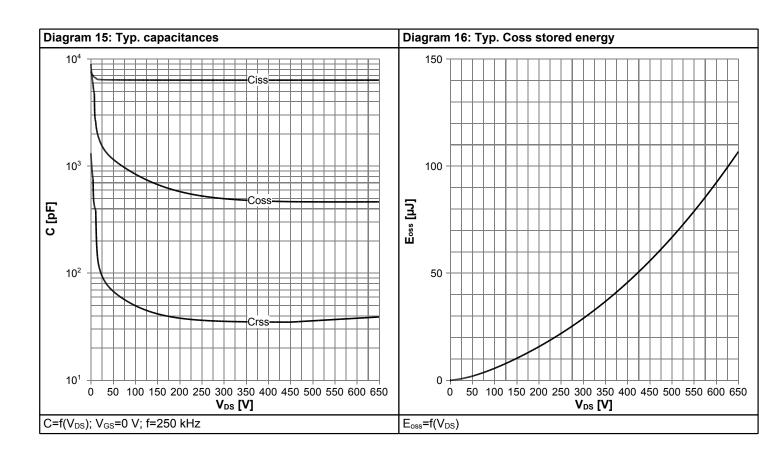




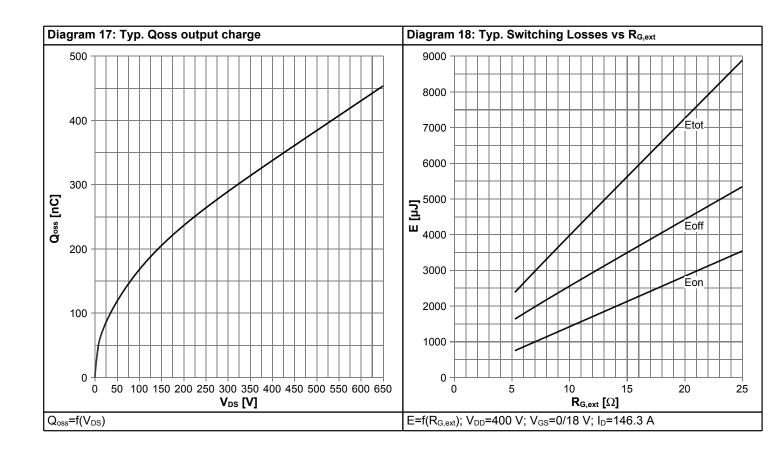


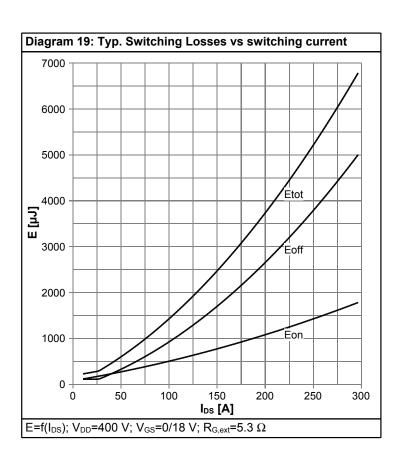














6 Test Circuits

Table 9 Body diode characteristics

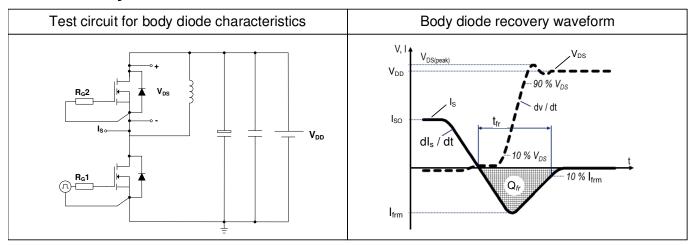


Table 10 Switching times

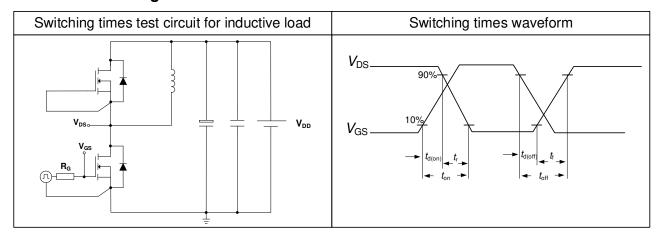
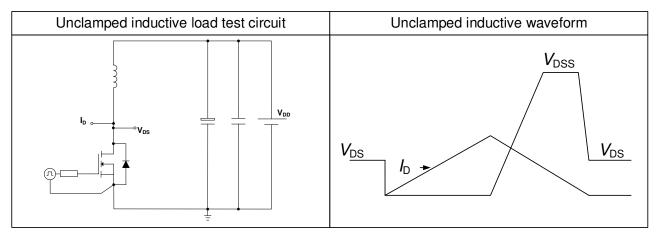
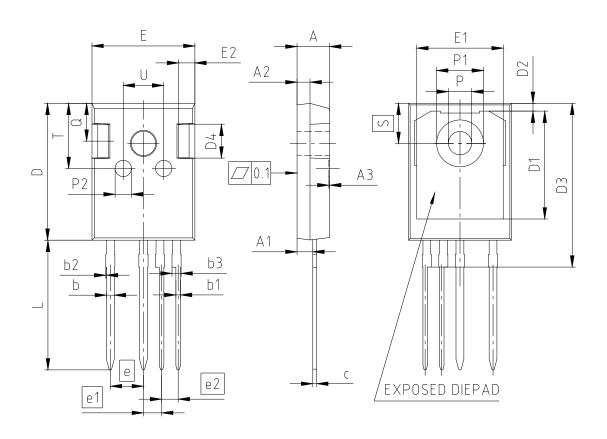


Table 11 Unclamped inductive load





7 Package Outlines



NOTES: DIMENSIONS DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS

PACKAGE - GROUP NUMBER:	PG-TO2	47-4-U02			
DIMENSIONS	MILLIM	IETERS	DIMENSIONS	MILLIM	IETERS
DIMENSIONS	MIN.	MAX.	DINIENSIONS	MIN.	MAX.
Α	4.90	5.10	E	15.70	15.90
A1	2.31	2.51	E1	13.10	13.50
A2	1.90	2.10	E2	2.40	2.60
A3	0.05	0.25	е	5.08	
b	1.10	1.30	e1	2.79	
b1	0.65	0.79	e2	2.54	
b2		0.20	N	4	
b3	1.34	1.44	L	19.80	20.10
С	0.58	0.66	øΡ	3.50	3.70
D	20.90	21.10	øP1	7.00	7.40
D1	16.25	16.85	øP2	2.40	2.60
D2	1.05	1.35	Q	5.60	6.00
D3	24.97	25.27	' S 6.15		15
D4	4.90	5.10	Т	9.80	10.20
			U	6.00	6.40

Figure 1 Outline PG-TO247-4, dimensions in mm



8 Appendix A

Table 12 Related Links

- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 Webpage: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 application note: www.infineon.com
- IFX CoolSiC CoolSiC™ MOSFET 650 V G2 simulation model: www.infineon.com
- IFX Design tools: www.infineon.com

CoolSiC™ MOSFET 650 V G2





Revision History

IMZA65R007M2H

Revision: 2024-03-05, Rev. 2.2

Previous Revision

Revision	Date	Subjects (major changes since last revision)
2.0	2023-10-10	Release of final version
2.1	2024-02-29	updated simulation model; included Eon and Eoff data and diagrams
2.2	2024-03-05	minor layout changes

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